Electronic Design.

How to Model, Measure, and Reduce EMI Noise

Electromagnetic-interference (EMI) disturbances are on the rise and becoming more intense due to more complex and powerful designs. Engineers can take several courses of action to tamp down the noise.

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ing harsh El his article offers ways to reduce and even avoid [elec](https://www.electronicdesign.com/magazine/50460)[tromagnetic interference \(EMI\)—](https://www.electronicdesign.com/magazine/50460)noise—in their designs. We'll look at some electronic system design examples [plagued or even damaged by EMI](https://www.electronicdesign.com/technologies/power/article/21281668/electronic-design-fear-and-mitigation-of-an-electromagnetic-pulse) and some tried and true methods of reducing or even eliminating harsh EMI disturbances.

EMI Noise Modeling

Two common-mode (CM) noise sources make up the CM noise model of the three-level T-type inverter $(3LT²I)$ used in adjustable-speed-drive (ASD) systems.⁵ The $3LT²I$ holds some significant advantages over a two-level voltage source inverter (2L-VSI), including:

• Silicon-carbide (SiC) MOSFETs allow for switching at

higher voltage and current.

• SiC MOSFETs enable low switching losses and higher operating temperatures.

The SiC MOSFET's fast switching speeds generate highvoltage slew rates, i.e., high dv/dt. This will create more EMI challenges, along with higher bearing currents in the motors, leading to deterioration in the insulation of the motor windings.

A couple of EMI standards, such as **[EN 50121](https://www.bing.com/ck/a?!&&p=28bb32d31bda50caJmltdHM9MTcxNjY4MTYwMCZpZ3VpZD0yNWNiZDhmNy1lMzBhLTYyYjUtMWE0MS1jY2FlZTI4NDYzM2MmaW5zaWQ9NTUxOQ&ptn=3&ver=2&hsh=3&fclid=25cbd8f7-e30a-62b5-1a41-ccaee284633c&psq=en+50121&u=a1aHR0cHM6Ly93d3cuZWxlbWVudC5jb20vbW9yZS1zZWN0b3JzL2VuLTUwMTIxLXJhaWx3YXktZW1jLXN0YW5kYXJkcyM6fjp0ZXh0PVdoYXQlMjBpcyUyMEVOJTIwNTAxMjElMjBUaGUlMjBmaXZlJTIwc3RhbmRhcmRzJTIwcHJvdmlkZSxhbmQlMjBpbW11bml0eSUyMGZvciUyMGVxdWlwbWVudCUyMG9wZXJhdGluZyUyMHdpdGhpbiUyMHRoZSUyMHJhaWx3YXku&ntb=1)** and **[IEC](https://d.docs.live.net/4d52f0aa6e33db8f/Documents/ED%20articles/TI%20Series/May%202024/Low%20EMI/Measuring%20and%20reducing%20EMI%2005262024.docx)** [61800,](https://d.docs.live.net/4d52f0aa6e33db8f/Documents/ED%20articles/TI%20Series/May%202024/Low%20EMI/Measuring%20and%20reducing%20EMI%2005262024.docx) provide the limits of EMI emissions, which can ensure that the system will be electromagnetically compatible within its environment. The EMI noise modeling of the 2L-VSI has been widely conducted, as seen in literature.

1. Shown is the topology of a 3LT2I for an ASD system with a line impedance stabilization network (LISN), along with parasitic capacitances. (Image courtesy of Reference 1)

Each phase of a 2L-VSI has just one voltage varying node. However, the three-level neutral point clamped (3L-NPC) maintains three voltage varying nodes while the $3LT²I$ has two voltage varying nodes. Unfortunately, the increase in voltage-varying nodes tends to complicate the EMI modeling of the three-level inverter topologies.

Many models of the three-level inverter (mainly with the 3L-NPC) focus on grid or photovoltaic applications. Unfor-

2. This is a topological diagram of a proposed SiC module. (Image courtesy of Reference 7) bare dies. The largest current loop is

tunately, no study has occurred for the EMI modeling of the 3LT2I for any ASD system *(Fig. 1)*.

Using the EMI Reduction Method for Power Modules

High-power integrated power modules have a very compact design with a high dv/dt slew rate. These kinds of power modules are quite susceptible to EMI.7

Designers have proposed using a vertical module design,

which displays improved EMI performance, over a wire-bonded module. Another proposed concept involves a novel EMI simulation method that utilizes [ANSYS](https://www.ansys.com/company-information/ansys-simulation-software?utm_source=bing&utm_medium=paid-search&utm_campaign=brand&utm_content=digital_simulation_copr15br_contact_contact-us_brand-general-brand-search_1a_en_global&utm_term=ansys&campaignid=7013g000000cXB4AAM&creative=&keyword=ansys&matchtype=e&network=o&device=c&s_kwcid=AL!17240!3!!e!!o!!ansys&msclkid=031644a30d6e1e5e9d3522f522310644) EM tools.

We can analyze the EMI mechanism of a complete SiC MOSFET integrated power module by examining the EMI coupling paths in both CM and differential-mode (DM) interference *(Fig. 2)*.

The upper and lower devices within the phase leg module are made up of three bare-die MOSFETs in parallel along with three anti-paralleled diode

3. Here's a 3D model of the proposed phase leg SiC module, along with adjacent coupling capacitors and a maximum current loop path. (Image courtesy of Reference 7)

made up of DIODE-H and MOS-L, which have the highest overvoltage and the maximum loop inductance. We find that the overvoltage of the power devices will increase the EMI in the high-frequency domain.

So, from *Figure 2*, the upper and lower devices within the phase leg module are made up of three paralleled MOSFET bare die. We can see that the largest current loop is made up of MOS-L and DIODE-H; this has the highest overvoltage with the maximum loop inductance. Unfortunately, the overvoltage of the power devices would increase the EMI within the high-frequency domain.

We now must decrease the large loop inductance that dominates the EMI in the high-frequency domain. What's proposed is a packaging structure with an adjacent decoupling concept that has many split decoupling capacitors, which will be between the power devices *(Fig. 3)*. The 3D model in *Figure 3* identifies a smaller current loop path.

Simulating the Power Module

Finally, a simulation methodology that organizes co-simulation techniques, using ANSYS EM tools, predicts radiated and conducted EMI from the power electronic module. A synchronous buck converter is simulated via ANSYS Simplorer software. It's able to import the electrical parameters of the full-SiC power module from the ANSYS Q3D software. A commercial, complete SiC MOSFET integrated power module, and a self-created one, are tested and compared, which verifies the EMI model method.

References

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